

**Notice of References Cited**

Application/Control No.

10/675,735

Applicant(s)/Patent Under  
Reexamination  
SHIN ET AL.

Examiner

Holly Rickman

Art Unit

1773

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
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**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	Q					
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	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Sun et al., Long-range order and short-range order study on CoCrPt/Ti films by synchrotron x-ray scattering and extended x-ray absorption fine structure spectroscopy, May 2002, J Appl Phys, Vol. 91, No 10, 7182-7184.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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